

Notice of References Cited

Application/Control No.

10/537,277

Applicant(s)/Patent Under
Reexamination
ONODA, YOSHIO

Examiner

NED A. WALKER

Art Unit

3781

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,157,308 A	11-1964	FOSTER JOHN A	220/669
*	B	US-3,419,181 A	12-1968	STEC FREDERICK J	220/258.2
*	C	US-3,463,349 A	08-1969	VIGNATI CARLO; et. al.	220/795
*	D	US-3,973,719 A	08-1976	Johnson et al.	229/5.6
*	E	US-4,328,905 A	05-1982	Hardt, Jean	220/258.2
*	F	US-4,533,064 A	08-1985	Kawamata et al.	220/273
*	G	US-4,557,414 A	12-1985	Ford et al.	229/5.5
*	H	US-4,708,257 A	11-1987	Deline, Douglas N.	220/257.2
*	I	US-4,749,100 A	06-1988	Eberhart, Ray	220/792
*	J	US-4,752,016 A	06-1988	Eads, Stephen R.	220/253
*	K	US-4,773,557 A	09-1988	Ohta, Toshimichi	220/258.2
*	L	US-4,869,389 A	09-1989	Cerrone, Jr., Frank J.	220/713
*	M	US-4,925,051 A	05-1990	Herbst, David H.	220/713

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
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	X					

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,927,048 A	05-1990	Howard, Roy T.	220/716
*	B	US-4,938,379 A	07-1990	Kellner, Louis W.	220/370
*	C	US-4,961,510 A	10-1990	Dvoracek, Frank	220/713
*	D	US-5,105,964 A	04-1992	Heath, William D.	220/784
*	E	US-5,108,003 A	04-1992	Granofsky, Barry P.	220/257.2
*	F	US-5,273,176 A	12-1993	Diaz, Eusebio M.	220/258.2
*	G	US-5,346,088 A	09-1994	Brimo, II, Joseph	220/806
*	H	US-5,452,818 A	09-1995	Yost, Kenneth J.	220/258.2
*	I	US-5,647,497 A	07-1997	Labbe, Andre	220/257.2
*	J	US-5,692,633 A	12-1997	Gordon, Herman	220/253
*	K	US-5,855,288 A	01-1999	Dallas, Jr., Milton R.	215/228
*	L	US-5,984,127 A	11-1999	Fenton, Robert C.	220/254.1
*	M	US-6,073,797 A	06-2000	Barous, Paul R.	220/716

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

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	U					
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	W					
	X					

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-D448,669 S	10-2001	Carducci et al.	D9/454
*	B	US-6,296,137 B1	10-2001	Bj.o slashed.msen, Petter Konrad	220/257.2
*	C	US-2002/0008109 A1	01-2002	Hirota et al.	220/258
*	D	US-6,338,418 B1	01-2002	Derosé, Mark V.	220/257.2
*	E	US-2002/0088802 A1	07-2002	DeRose, Mark V.	220/258.2
*	F	US-6,450,358 B1	09-2002	Berro, Carlo	220/258.2
*	G	US-6,457,597 B2	10-2002	Hirota et al.	220/258.2
*	H	US-2003/0010787 A1	01-2003	Dalton et al.	220/912
*	I	US-2003/0102313 A1	06-2003	Weber, Joseph	220/254.4
*	J	US-2003/0168457 A1	09-2003	Wang, Hung-Yu	220/258.2
*	K	US-2003/0222083 A1	12-2003	Pladsbjerg, Christina	220/254.3
*	L	US-2004/0000551 A1	01-2004	Flink et al.	220/258.3
*	M	US-2004/0020934 A1	02-2004	Olsen, Bent Hjort	220/711

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,708,748 B1	03-2004	Kronseider et al.	156/570
*	B	US-2004/0099663 A1	05-2004	Griffis, Darren Lee	220/258.2
*	C	US-6,910,598 B2	06-2005	Gotz et al.	220/258.3
*	D	US-2005/0218013 A1	10-2005	Tabeshnekoo, Masoud	206/145
*	E	US-7,017,769 B1	03-2006	Talmon, Enrico	220/258.2
*	F	US-7,066,346 B2	06-2006	Bazela et al.	220/257.2
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	X				

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